

# MI8412-VB Datasheet

# N-Channel 20 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (TYP.)			
20	0.0055 at V <sub>GS</sub> = 4.5V	58	9.4 nC			
20	0.0057 at V <sub>GS</sub> = 2.5 V	45	9.4 110			

#### **FEATURES**

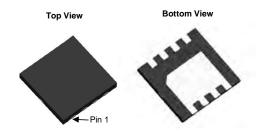
- Trench power MOSFET
- 100 % R<sub>g</sub> and UIS tested

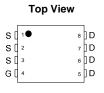
# RoHS COMPLIANT HALOGEN FREE

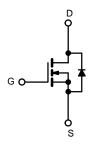
#### **APPLICATIONS**

- High power density DC/DC
- Synchronous rectification
- Embedded DC/DC









N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	20	V		
Gate-Source Voltage		V <sub>GS</sub>	+12	□	
	T <sub>C</sub> = 25 °C		58		
Continuous Dusin Comment (T. 150 °C)	T <sub>C</sub> = 70 °C		46		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	19.8 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		15.8 <sup>b, c</sup>		
Pulsed Drain Current (t = 300 μs)	I <sub>DM</sub>	150	A		
Continuous Courses Drain Diada Current	T <sub>C</sub> = 25 °C		14.1		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	l <sub>S</sub>	3.2 b, c		
Single Pulse Avalanche Current	. 0.4!!	I <sub>AS</sub>	15		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11.25	mJ	
	T <sub>C</sub> = 25 °C		31.2		
Manian and Danier Distriction	T <sub>C</sub> = 70 °C		20	10/	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.6 <sup>b, c</sup>	W	
	T <sub>A</sub> = 70 °C		2.3 b, c	7	
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	.0		
Soldering Recommendations (Peak Temperatur	_	260	°C		

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient b, f	t ≤ 10 s	$R_{thJA}$	24	34	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	3	4	O/ VV	

#### Notes

- a. Based on  $T_C = 25$  °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. The DFN3X3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



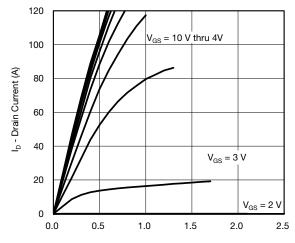
<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, unle	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static	01202					1	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	20	_	_		
Drain-Source Breakdown Voltage (transient) <sup>c</sup>	V <sub>DSt</sub>	$V_{GS} = 0 \text{ V}, I_{D(aval)} = 15 \text{ A}, t_{transient} = 50 \text{ ns}$	26	_	_	V	
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>	I <sub>D</sub> = 250 μA		20	_	mV/°	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			-4.6	_	C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.5	-	1.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 12V	-	_	± 100	nA	
Cate Course Loanage	1000	$V_{DS} = 20 \text{ V}, V_{GS} = 12 \text{ V}$	_	_	1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$ - $V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$ -		_	10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30	_	-	Α	
On State Brain Surrent	الرon)	$V_{GS} = 4.5 \text{ V}, V_{GS} = 10 \text{ A}$	-	0.0055		+ ^-	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 8 A	_	0.0057	-	Ω	
Forward Transconductance <sup>a</sup>	O.	$V_{DS} = 10 \text{ V}, I_D = 10 \text{ A}$		65		S	
Dynamic b	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, 10 = 10 A	<u>-</u>	00			
Input Capacitance	C		_	1450	_	l	
· · ·	Ciss	-		445		pF	
Output Capacitance Reverse Transfer Capacitance	Coss	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-		-		
<u>'</u>	C <sub>rss</sub>	-		38	- 0.050	4	
C <sub>rss</sub> /C <sub>iss</sub> Ratio		V 45 V V 40 V L 40 A	-	0.026	0.052		
Total Gate Charge	$Q_g$	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	19.4	29	nC	
Oata Carrea Oharra	_	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$	-	9.4	14		
Gate-Source Charge	Q <sub>gs</sub>		-	4	-		
Gate-Drain Charge	Q <sub>gd</sub>	V 45V V 0V	-	1.8	-	1	
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V	-	12.5	-		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.4	1.65	3.3	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>	-	-	9	18	4	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_L = 1.5 \Omega$		8	16		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	18	36	ns	
Fall Time	t <sub>f</sub>		-	8	16		
Turn-On Delay Time	t <sub>d(on)</sub>		-	15	30		
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_L = 1.5 \Omega$	-	12	24		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		18	36		
Fall Time	t <sub>f</sub>			9	18		
<b>Drain-Source Body Diode Characteristics</b>	T	,				1	
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C	-	-	14.1	Α	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	80		
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 3 A	-	0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	24	48	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$	I <sub>F</sub> = 10 A, dI/dt = 100 A/μs,	-	14	28	nC	
Reverse Recovery Fall Time	ta	T <sub>J</sub> = 25 °C	-	12	-	ns	
Reverse Recovery Rise Time	t <sub>b</sub>	]	-	12	-		

#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c.  $T_{CASE} = 25$  °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

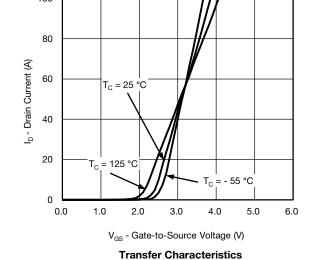
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

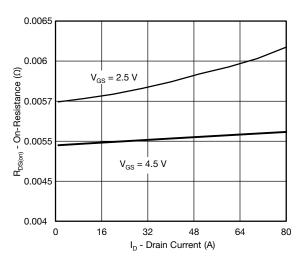




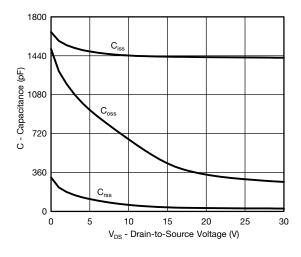
 ${\rm V}_{\rm DS}$  - Drain-to-Source Voltage (V)

#### **Output Characteristics**

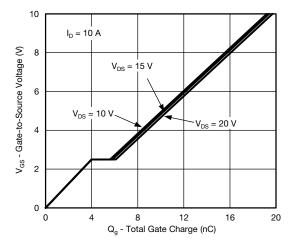




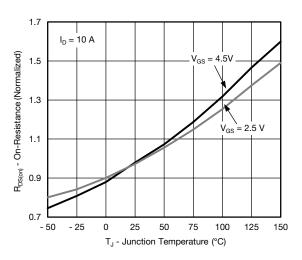
On-Resistance vs. Drain Current



Capacitance

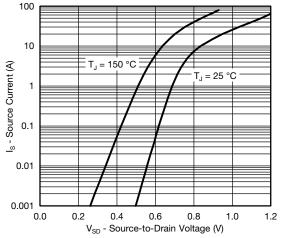


**Gate Charge** 

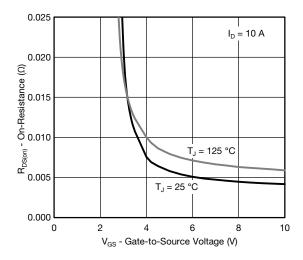


On-Resistance vs. Junction Temperature

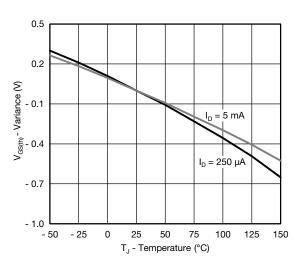




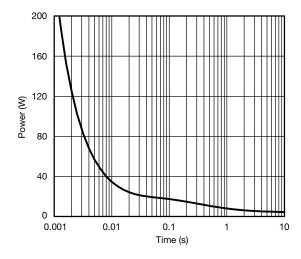
Source-Drain Diode Forward Voltage



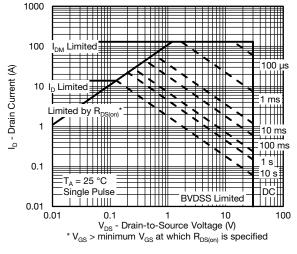
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 

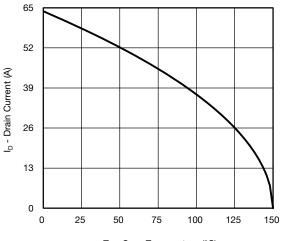


Single Pulse Power, Junction-to-Ambient



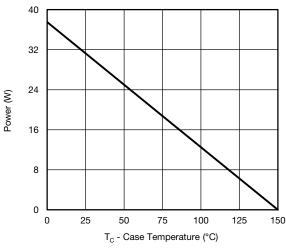
Safe Operating Area

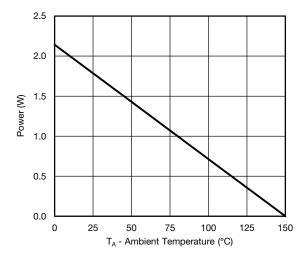




T<sub>C</sub> - Case Temperature (°C)

#### **Current Derating\***



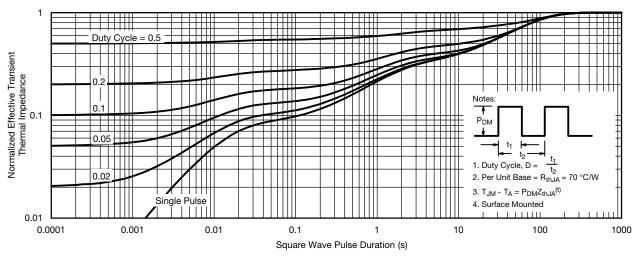


Power, Junction-to-Case

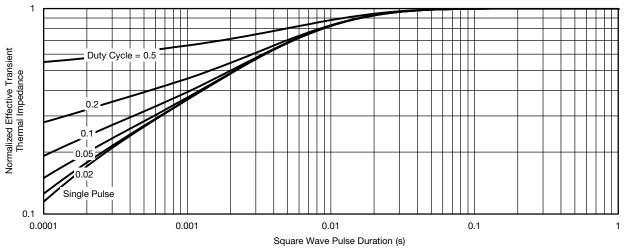
Power, Junction-to-Ambient

 $<sup>^*</sup>$  The power dissipation  $P_D$  is based on  $T_{J \text{ (max.)}} = 150 \,^{\circ}\text{C}$ , using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



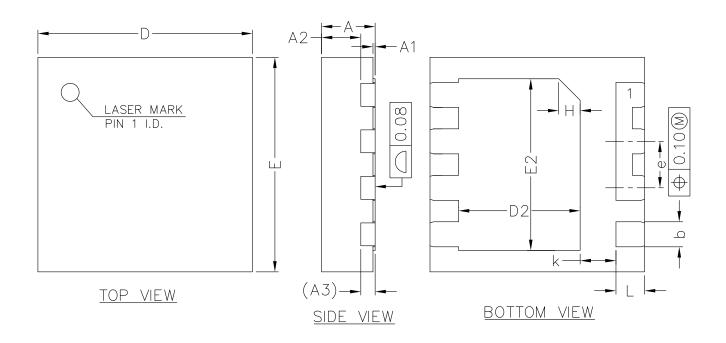


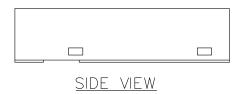
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX		
Α	0.70	0.75	0.80		
A1	0.00	0.02	0.05		
A2	0.50	0.55	0.60		
А3	0.20REF				
b	0.30	0.35	0.40		
D	2.90	3.00	3.10		
Е	2.90	3.00	3.10		
D2	1.60	1.70	1.80		
E2	2.30	2.40	2.50		
е	0.55	0.65	0.75		
K	0.40	0.50	0.60		
L	0.35	0.40	0.45		

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